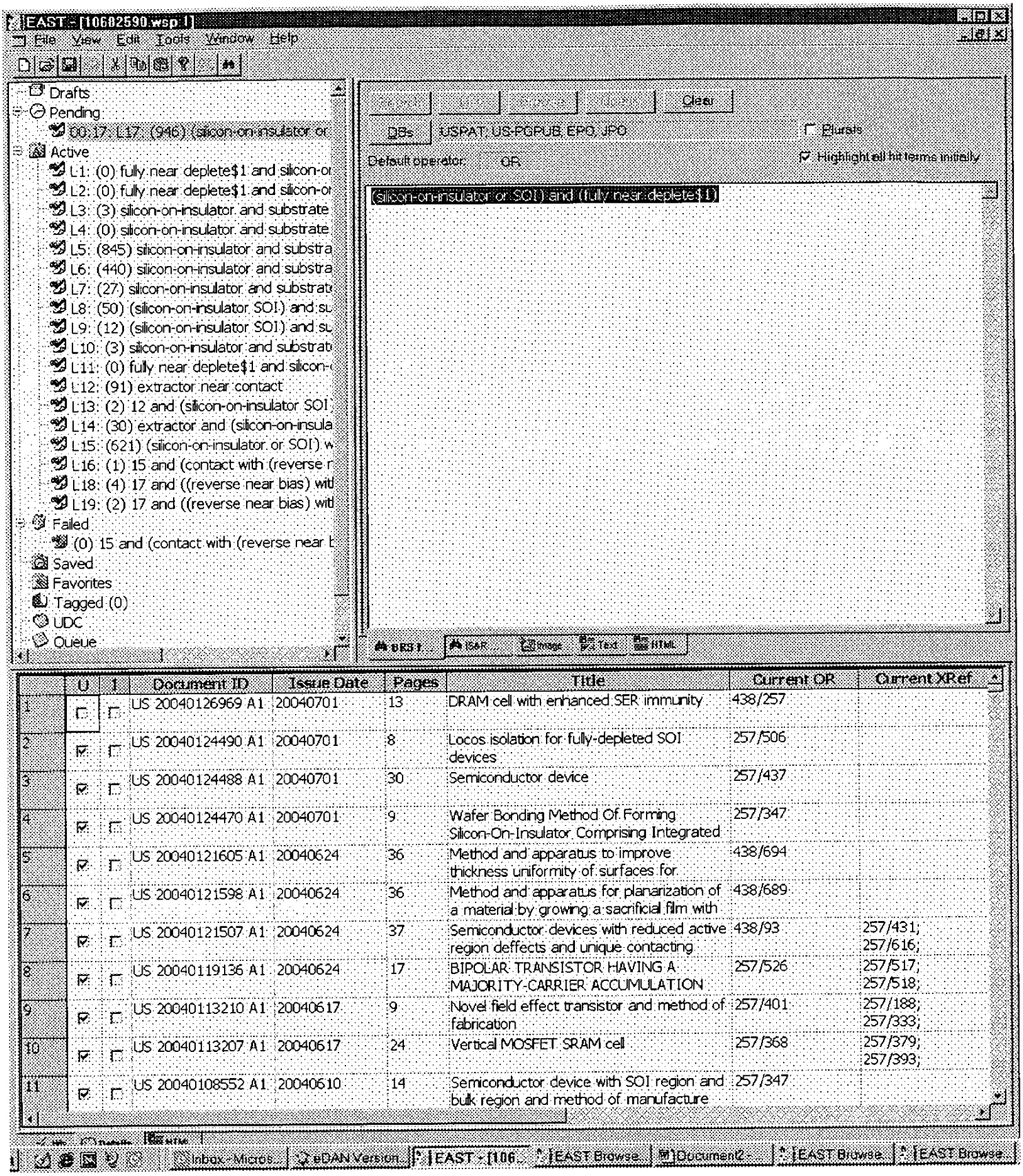

	U	I	Document ID	Issue Date	Pages	Title	Current OR	Current XRef
1	☐	☐	US 20040126969 A1	20040701	13	DRAM cell with enhanced SER immunity	438/257	
2	☑	☐	US 20040124490 A1	20040701	8	Locos isolation for fully-depleted SOI devices	257/506	
3	☑	☐	US 20040124488 A1	20040701	30	Semiconductor device	257/437	
4	☑	☐	US 20040124470 A1	20040701	9	Wafer Bonding Method Of Forming Silicon-On-Insulator Comprising Integrated	257/347	
5	☑	☐	US 20040121605 A1	20040624	36	Method and apparatus to improve thickness uniformity of surfaces for	438/694	
6	☑	☐	US 20040121598 A1	20040624	36	Method and apparatus for planarization of a material by growing a sacrificial film with	438/689	
7	☑	☐	US 20040121507 A1	20040624	37	Semiconductor devices with reduced active region deffects and unique contacting	438/93	257/431; 257/616;
8	☑	☐	US 20040119136 A1	20040624	17	BIPOLAR TRANSISTOR HAVING A MAJORITY-CARRIER ACCUMULATION	257/526	257/517; 257/518;
9	☑	☐	US 20040113210 A1	20040617	9	Novel field effect transistor and method of fabrication	257/401	257/188; 257/333;
10	☑	☐	US 20040113207 A1	20040617	24	Vertical MOSFET SRAM cell	257/368	257/379; 257/393;
11	☑	☐	US 20040108552 A1	20040610	14	Semiconductor device with SOI region and bulk region and method of manufacture	257/347	